

Notice of References Cited	Application/Control No. 10/760,120		Applicant(s)/Patent Under Reexamination HILTUNEN ET AL.	
	Examiner Albert H. Cutler		Art Unit 2622	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0065102	05-2002	Miyake et al.	455/556
*	B	US-2002/0057468	05-2002	Segawa et al.	358/509
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 11-191865	07-1999	Japan	Takanao et al.	N/A
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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